

A LOW-COST, RECONFIGURABLE THIN- FILM INSPECTION SYSTEM

TOWARDS LARGE AREA THIN-FILM REFLECTOMETRY

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A LOW-COST, RECONFIGURABLE THIN-FILM INSPECTION
SYSTEM

OVERVIEW

- Motivation
 - Challenges
- State of the Art
- Approach
- Status
- Future work

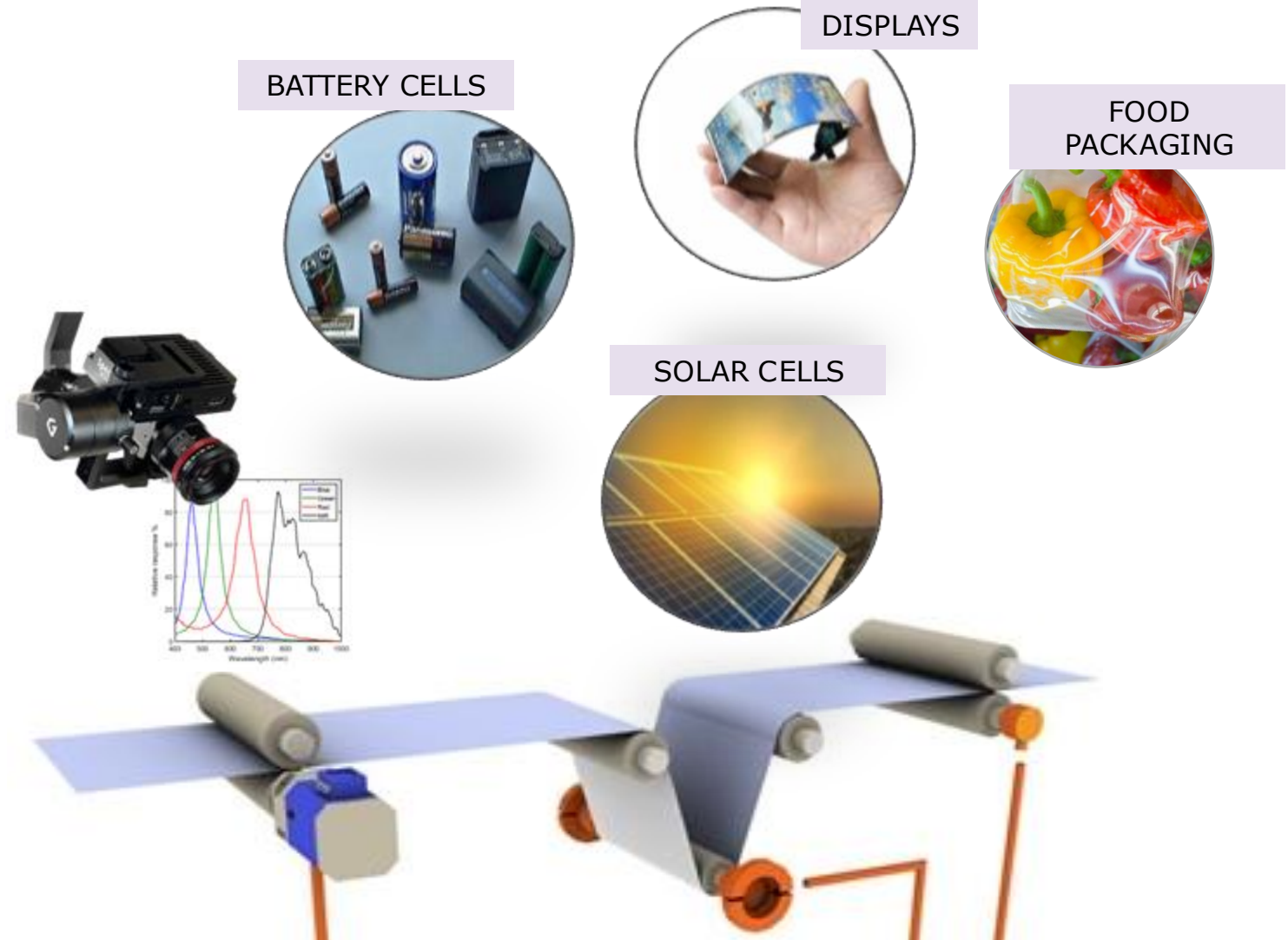


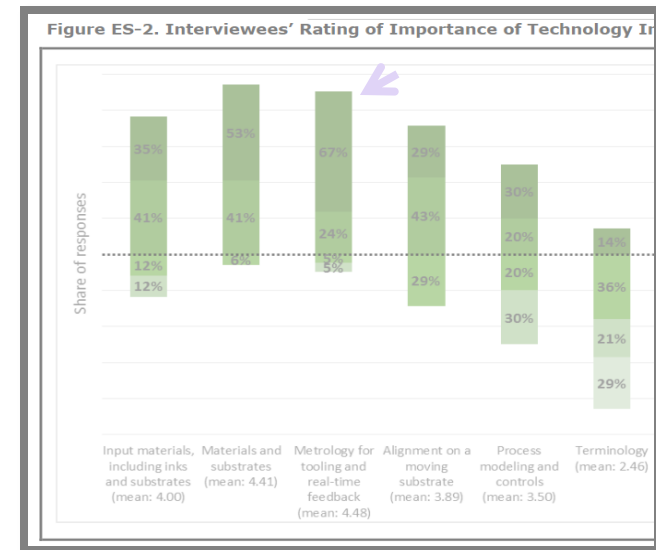
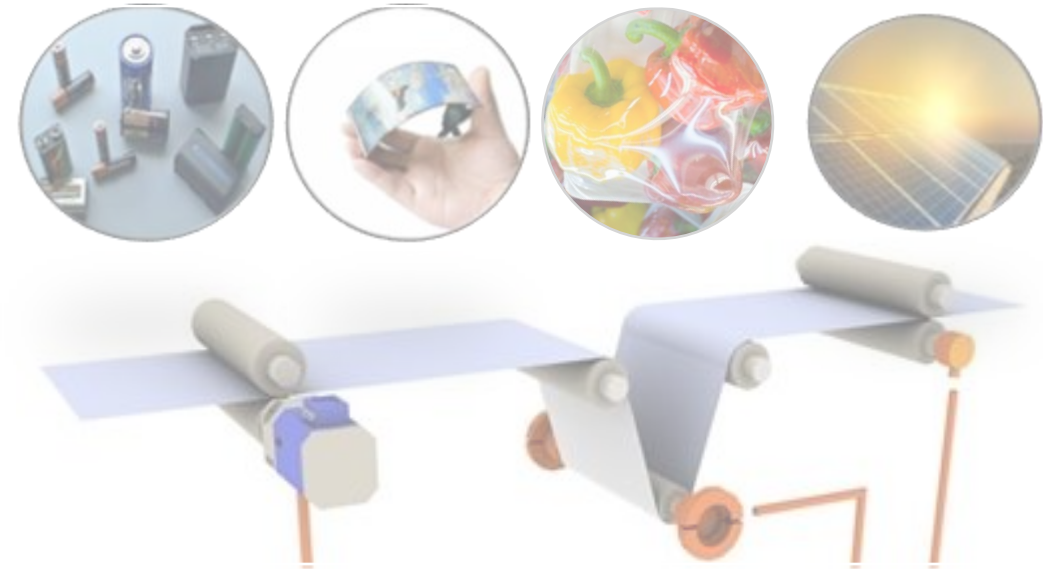
ILLUSTRATION OF INDUSTRIAL THIN-FILM INSPECTION

MOTIVATION

- “Metrology has not kept up with thin-film manufacturing speeds” (Maize et al, 2022; NIST 2016)
- Large-area thin films are everywhere!
 - used in PV, displays, batteries, and packaging
- Industry often needs 100% inline, real-time inspection

CHALLENGES

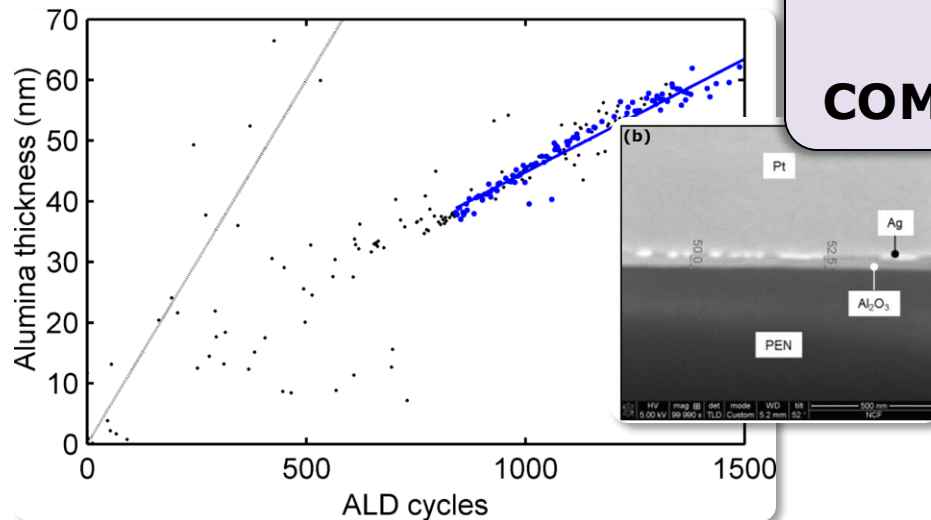
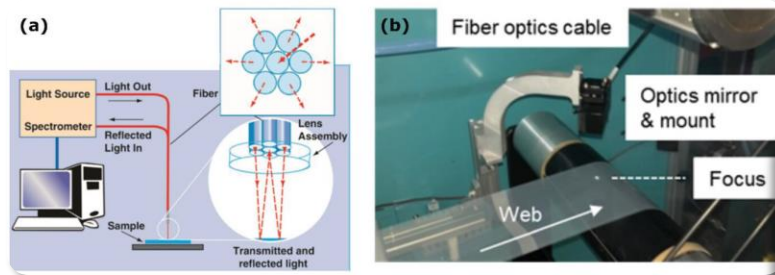
- Metrology is too computationally heavy or too slow
- Also, too expensive



IMPORTANCE OF METROLOGY IN R2R MANUFACTURING

STATE OF THE ART

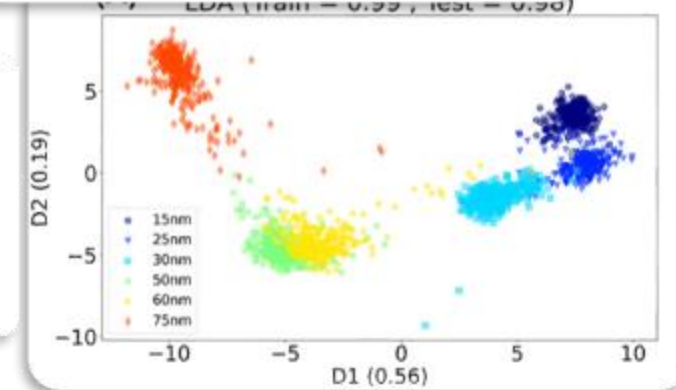
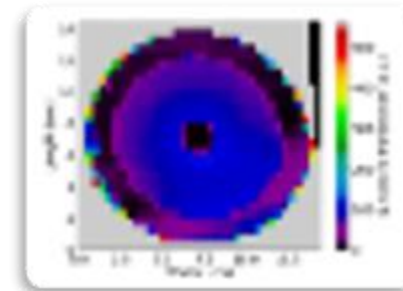
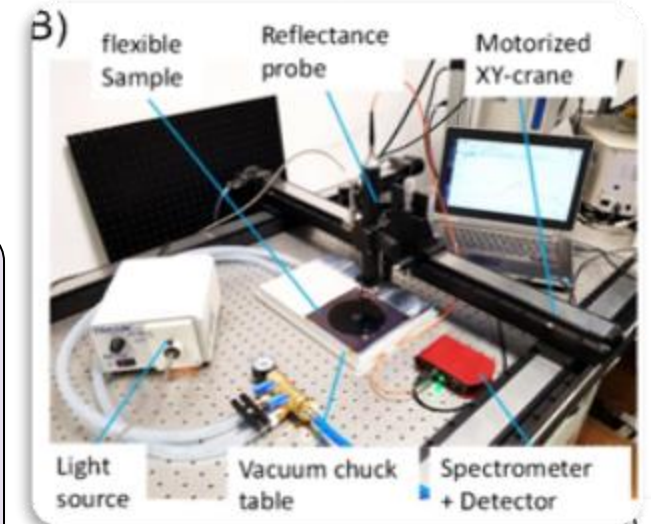
POINT THIN FILM INSPECTION



FOR 52NM ALD MOVING AT 1M/S Al_2O_3 (2014)

ALL USE FULL
REFLECTANCE SPECTRA,
WHICH CAN BE
COMPUTATIONALLY HEAVY

AREA MAPPING

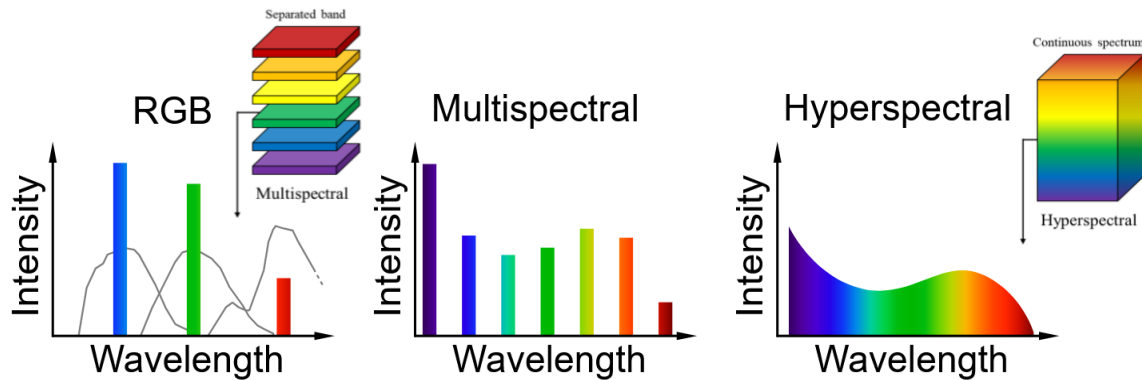


25NM Al_xO FILM ON SILICON, (ENRIC, 2021)

BACKGROUND

Reflectance spectra can be used to estimate film uniformity.

- Multispectral and RGB Cameras have **less spectral resolution**
- Each pixel creates has



REDUCED SPECTRAL RESOLUTION WITH HYPERSPECTRAL

APPROACH

- Use multispectral/RGB cameras instead
 - Less computationally heavy and
 - Less expensive

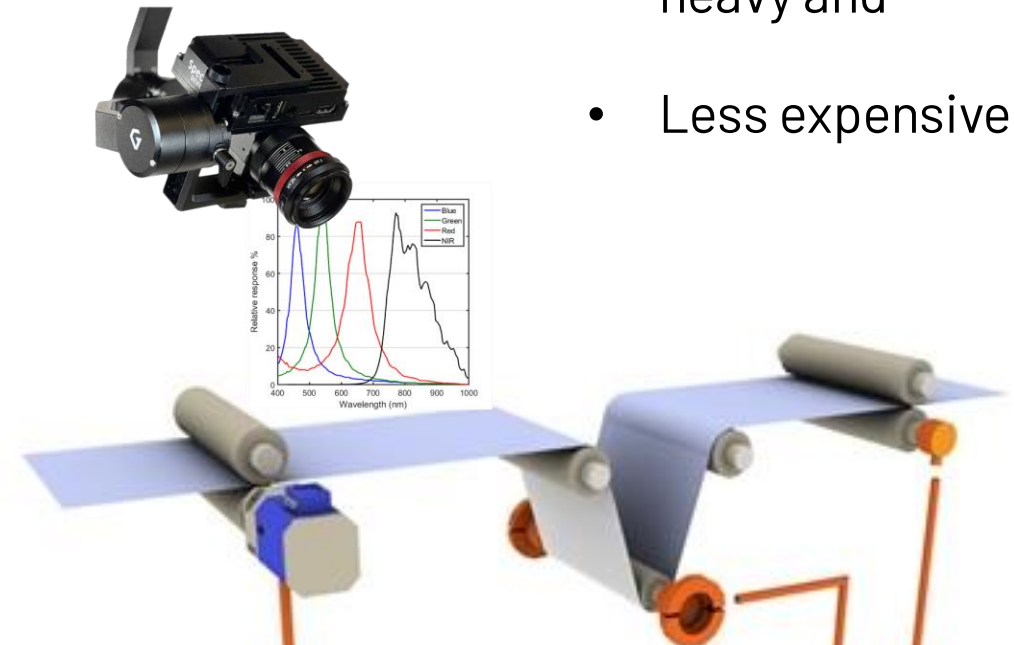
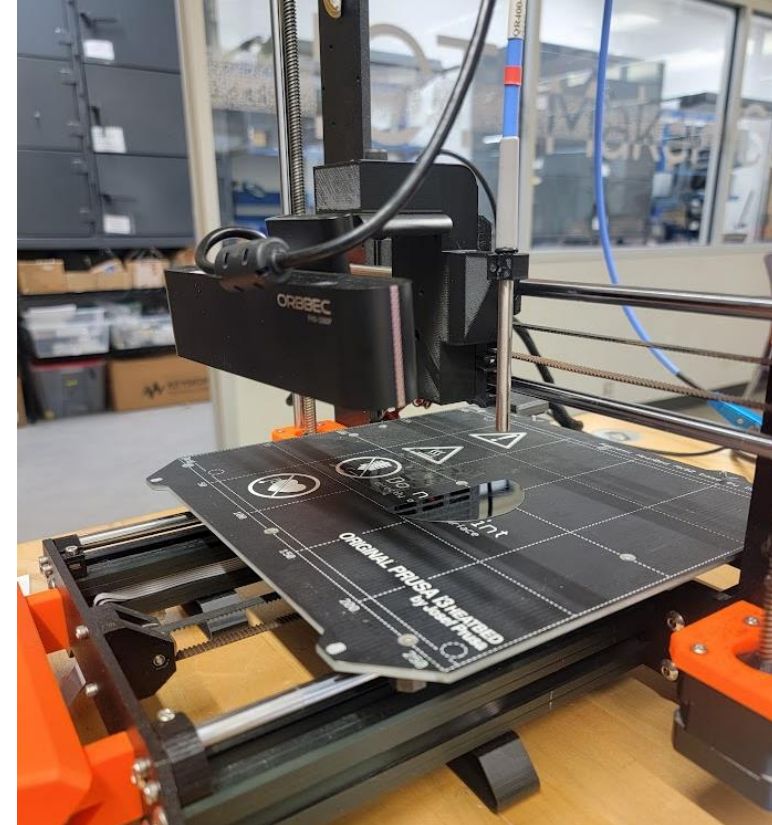
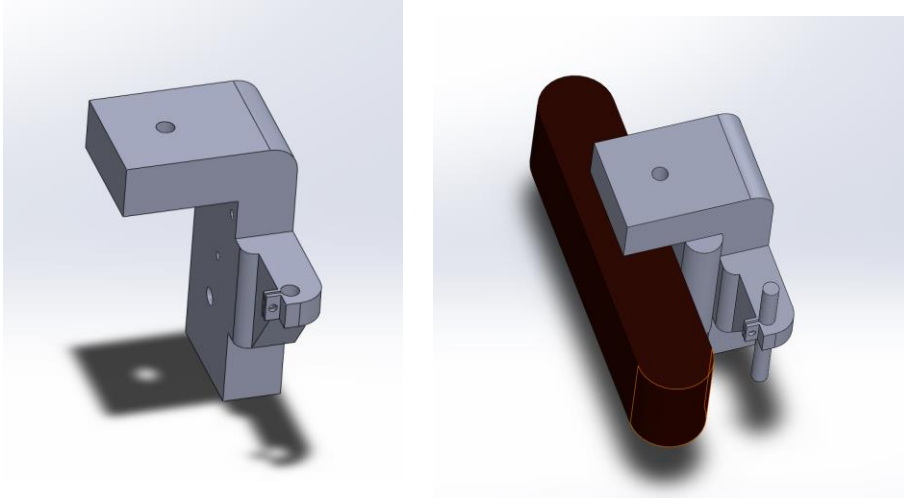


ILLUSTRATION OF INDUSTRIAL THIN-FILM INSPECTION

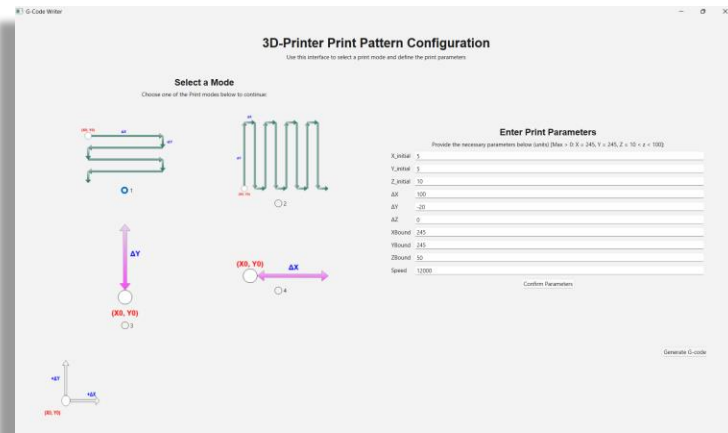
WORK SO FAR – GANTRY DESIGN

- Prusa 3D MK3s was adapted to create an operational gantry
- A rig was designed and built to attach camera and spectrometer to the gantry

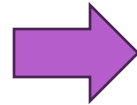


WORK SO FAR – USER INTERFACE

- A user interface was built to turn user instruction into machine procedure



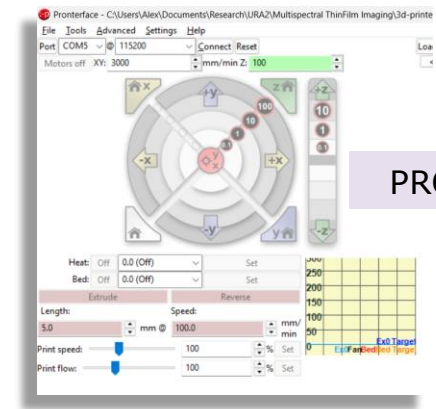
USER INTERFACE



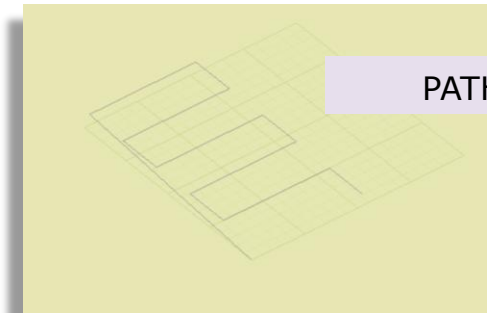
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3d-printer_scan_pattern_output.tx
File Edit View

G21
G90
G1 X5 Y200 Z10 F12000
G1 X105 F12000
G1 Y160 F12000
G1 X5 F12000
G1 Y120 F12000
G1 X105 F12000
G1 Y80 F12000
G1 X5 F12000
G1 Y40 F12000
G1 X105 F12000
G1 Y0 F12000
```

G-CODE

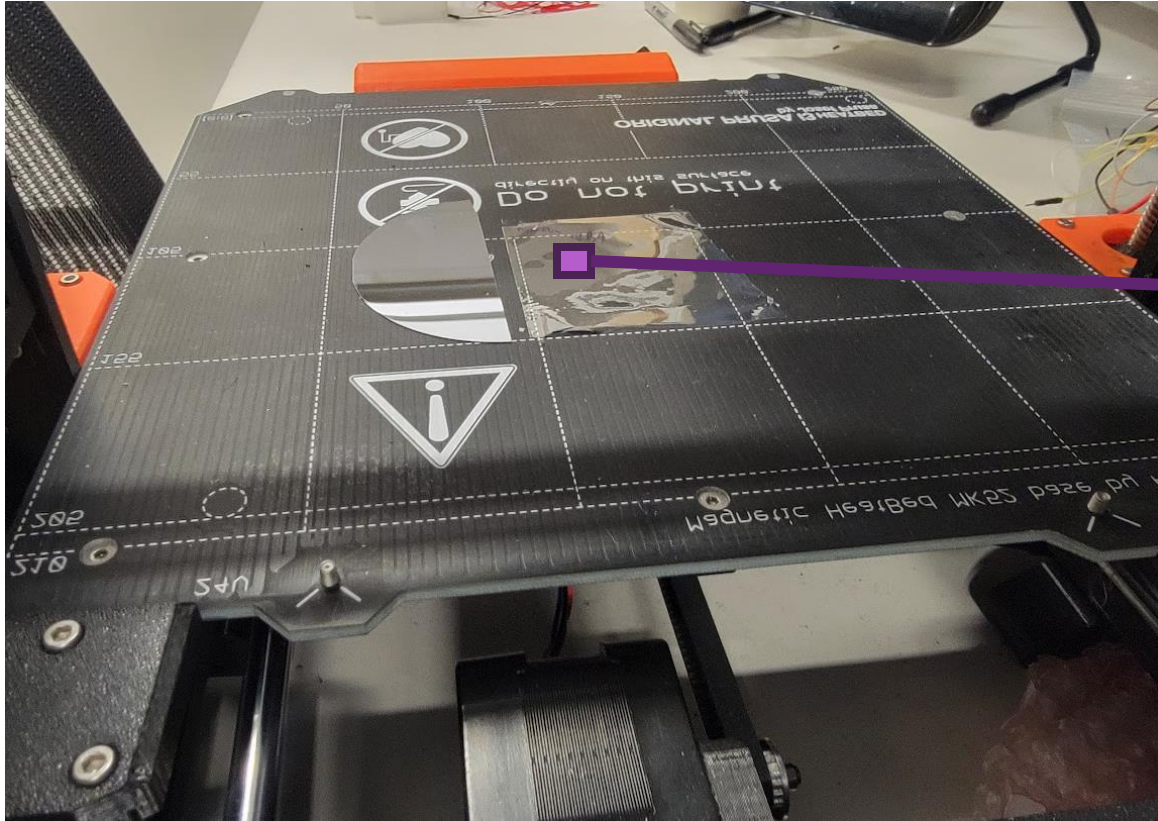


PRONTERFACE



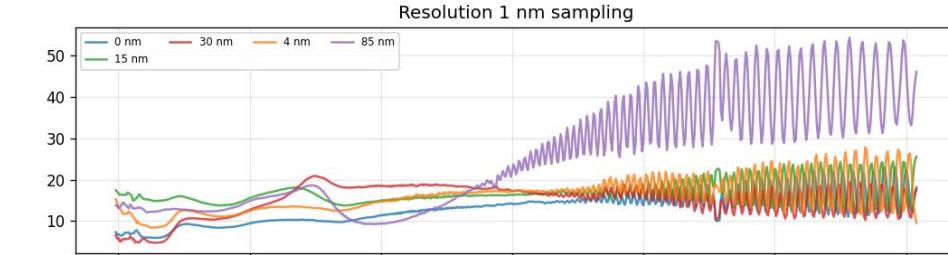
PATH

PRELIMINARY DATA

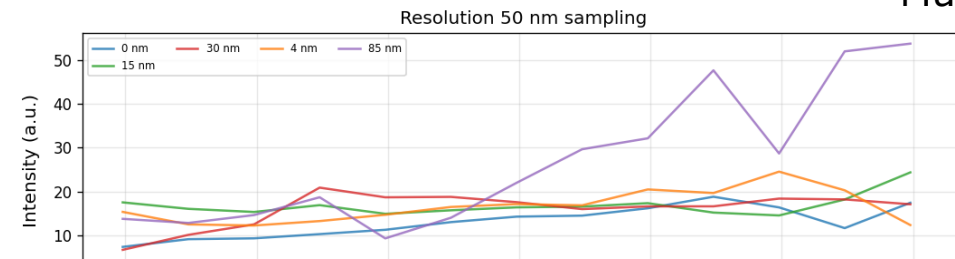


IMAGES OF SAMPLE ON STAGE

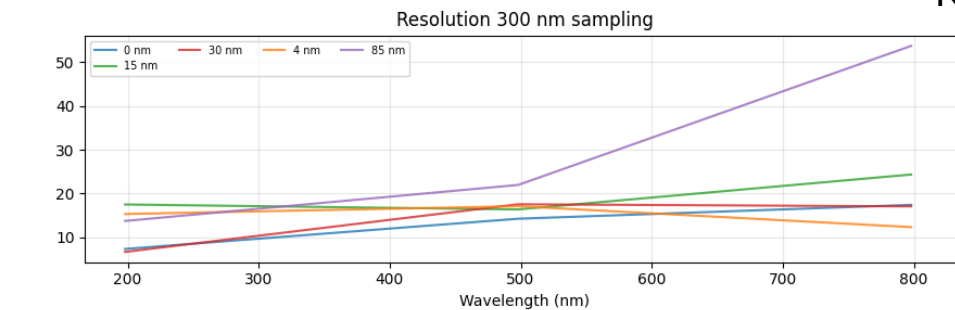
Spectrometer



Multispectral



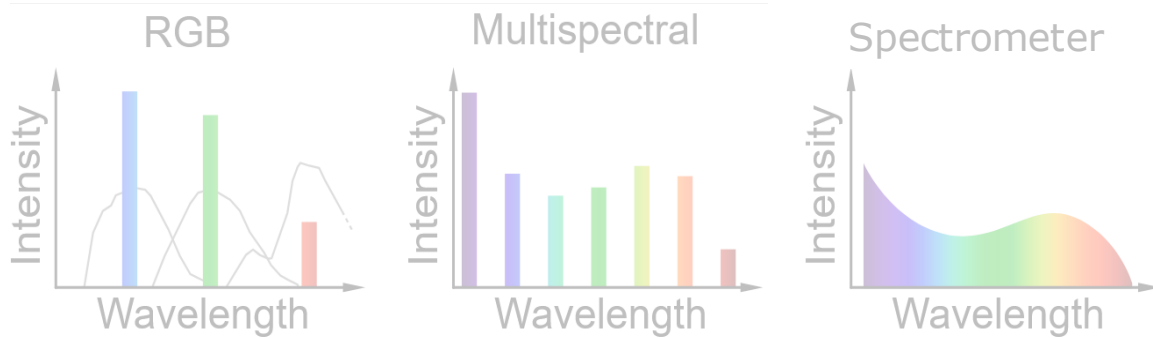
RGB



SPECTRAL RESOLUTION REDUCED BY BINNING AND AVERAGING

FUTURE WORK

- Improve UI and Camera rig
- Test on more samples (from partners)
- Increase metrology accuracy
- Integrate into real system



REDUCED SPECTRAL RESOLUTION WITH HYPERSPECTRAL

THANK YOU!

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Thank you! Questions?